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| 1 | PROCESSES JOINING INDEPENDENT CRYSTALS | 20 | ...Comprising a silicon crystal with oxygen containing impurity |
| 2 | PROCESSES OF GROWTH WITH A SUBSEQUENT STEP ACTING ON THE CRYSTAL TO ADJUST THE IMPURITY AMOUNT (E.G., DIFFUSING, DOPING, GETTERING, IMPLANTING) | 21 | ...Comprising a semiconductor with a charge carrier impurity |
| 3 | PROCESSES OF GROWTH WITH A SUBSEQUENT STEP OF HEAT TREATING OR DELIBERATE CONTROLLED COOLING OF THE SINGLE-CRYSTAL | 22 | ...Forming adjoining crystals of different compositions (e.g., junction) |
| 4 | PROCESSES OF GROWTH FROM SOLID OR GEL STATE (E.G., SOLID PHASE RECRYSTALLIZATION) | 23 | ..Shape defined by a solid member other than seed or product (e.g., edge-defined film-fed growth, Stepanov method) |
| 5 | ..Organic product | 24 | ...Embedded in product (e.g., string-stabilized web) |
| 6 | ..At pressure above 1 atmosphere | 25 | ...Defines a product with a hollow structure (e.g., tube) |
| 7 | ..Using heat (e.g., strain annealing) | 26 | ...Defines a flat product |
| 8 | ..Of amorphous precursor | 27 | ...Pulling includes a horizontal component |
| 9 | ..Epitaxy formation | 28 | ..Including non-coincident axes of rotation (e.g., relative eccentric) |
| 10 | ..Using temperature gradient (e.g., moving zone recrystallization) | 29 | ..Passing non-induced electric current through a crystal-liquid interface (e.g., Peltier) |
| 11 | PROCESSES OF GROWTH FROM LIQUID OR SUPERCRITICAL STATE | 30 | ..With liquid flow control or manipulation during growth (e.g., mixing, replenishing, magnetic levitation, stabilization, convection control, baffle) |
| 12 | ..Crucibleless process having movement of discrete droplets or solid particles to thin-film precursor (e.g., Verneuil method) | 31 | ...Including a sectioned crucible (e.g., double crucible, baffle) |
| 13 | ..Having pulling during growth (e.g., Czochralski method, zone drawing) | 32 | ...Using a magnetic field |
| 14 | ..With a step of measuring, testing, or sensing (e.g., using TV, photo, or X-ray detector or weight changes) | 33 | ...Replenishing of precursor during growth (e.g., continuous method, zone pulling) |
| 15 | ...With responsive control | 34 | ...Including significant cooling or heating detail |
| 16 |Shape defined by a solid member other than seed or product (e.g., edge-defined film-fed growth, Stepanov method) | 35 | ..With a significant technique for (a) preliminary preparation or growth starting or (b) product handling or growth ending (e.g., arrangement of or crystallography of seed) |
| 17 | ..With contact with an immiscible liquid (e.g., LEC) | | |
| 18 | ...Using a sectioned crucible or providing replenishment of precursor | | |
| 19 | ..Forming an intended mixture (excluding mixed crystal) (e.g., doped) | | |

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| 36 | ..Precursor intentionally contains an excess component or a non-product appearing component (e.g., solvent, flux, crystal lattice modifier) | 51 |Electromagnetic induction |
| 37 | ..Having moving solid-liquid-solid region | 52 |With liquid control (e.g., vibration damping, stabilizing, melt levitation focusing coil) |
| 38 | ..Including a step of measuring, testing, or sensing | 53 | ..Forming a single-crystal region by liquefying a region of a single-crystal and adjusting the composition of the liquid (e.g., alloying, regrowth) |
| 39 | ...With responsive control | 54 | ..Liquid phase epitaxial growth (LPE) |
| 40 | ..Liquid precursor penetrating only a portion of a single-crystal, thereby liquefying it, and single-crystal formation therefrom which adjoins the never-liquefied portion of the single-crystal (e.g., liquid wire migration) | 55 | ..With a step of measuring, testing, or sensing |
| 41 | ..Precursor composition intentionally different from product (e.g., excess component, non-product forming component, dopant, non-stoichiometric precursor, travelling solvent, flux) | 56 | ..Including change in a growth-influencing parameter (e.g., composition, temperature, concentration, flow rate) during growth (e.g., multilayer or junction or superlattice growing) |
| 42 | ...Product has an element in common with the unusable residual portion | 57 | ...Including a sliding boat system |
| 43 | ..Distinctly layered product (e.g., twin, SOI, epitaxial crystallization) | 58 | ..With pretreatment of epitaxy substrate (e.g., autodoping control, cleaning, polishing, leveling, masking) |
| 44 | ..Adjacent single-crystal product regions separately formed (e.g., multiple non-coextensive passes of a scanning laser) | 59 | ..Including a tipping system (e.g., rotation, pivoting) |
| 45 | ...Non-planar crystal grown (e.g., ELO) | 60 | ..Including a vertical dipping system |
| 46 | ..Movement includes a horizontal component | 61 | ..Including a sliding boat system |
| 47 | ..Flat, free-standing (i.e., substrate-free) product (e.g., ribbon, film, sheet) | 62 | ..Electric current controlled or induced growth |
| 48 | ..Solid heating means contacting the liquid (e.g., immersed) | 63 | ..Characterized by specified crystallography of the substrate |
| 49 | ..Liquid zone contacts only precursor and product solids (e.g., crucibleless, liquid encapsulant, float zone) | 64 | ..Precursor composition intentionally contains an excess component or a non-product appearing component (e.g., solvent, flux) |
| 50 | ..Liquefying by energy from an electromagnetic wave or electromagnetic particle or arc or plasma (e.g., radiant heat) | 65 | ...Having an element in common |
| | | 66 |Excess component or non-product appearing component contains an oxygen atom (e.g., hydrothermal) |
| | | 67 |Excess component or non-product appearing component contains a metal atom |

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| 68 | .Having growth from a solution comprising a solvent which is liquid at or below 20 degrees Celsius (e.g., aqueous solution) | 84 | FORMING FROM VAPOR OR GASEOUS STATE (E.G., VPE, SUBLIMATION) |
| 69 | ..With a step of measuring, testing, or sensing | 85 | .With a step of measuring, testing, or sensing |
| 70 | ..Growth accompanied by material removal (other than the product) from solution (e.g., solvent evaporation, osmosis) | 86 | ..With responsive control |
| 71 | ..At pressure above 1 atmosphere (e.g., hydrothermal processes) | 87 | .Forming a platelet shape or a small diameter, elongate, generally cylindrical shape (e.g., whisker, fiber, needle, filament) |
| 72 | ...Quartz (SiO ₂) product | 88 | .With decomposition of a precursor (except impurity or dopant precursor) composed of diverse atoms (e.g., CVD) |
| 73 | .Havin growth from molten state (e.g., solution melt) | 89 | ..Including change in a growth-influencing parameter (e.g., composition, temperature, concentration, flow rate) during growth (e.g., multilayer or junction or superlattice growing) |
| 74 | ..Including change in a growth-influencing parameter (e.g., composition, temperature, concentration, flow rate) during growth (e.g., multilayer or junction or superlattice growing) | 90 | ...With pretreatment of substrate (e.g., coacting ablating) |
| 75 | ..Forming a platelet shape or a small diameter, elongate, generally cylindrical shape (e.g., whisker, fiber, needle, filament) (e.g., VLS method) | 91 | ...With a chemical reaction (except ionization) in a disparate zone to form a precursor |
| 76 | ..Using a scavenger agent (e.g., remove, add, deplete, or redistribute impurity or dopant) | 92 | ...Using an energy beam or field, a particle beam or field, or a plasma (e.g., ionization, PECVD, CBE, MOMBE, RF induction, laser) |
| 77 | ..Gas or vapor state precursor or overpressure | 93 | ...With significant flow manipulation or condition, other than merely specifying the components or their sequence or both |
| 78 | ..Precursor composition intentionally different from product (e.g., excess component, non-product forming component, dopant, non-stoichiometric precursor, solvent, flux) | 94 | ..With pretreatment or preparation of a base (e.g., annealing) |
| 79 | ..Unusable portion contains a metal atom (e.g., diamond or CBN growth in metal solvent) | 95 | ...Coating (e.g., masking, implanting) |
| 80 | ...Unusable portion contains an oxygen atom (e.g., oxide flux) | 96 |For autodoping control |
| 81 | ..Growth confined by a solid member other than seed or product (e.g., Bridgman-Stockbarger method) | 97 | ...Material removal (e.g., etching, cleaning, polishing) |
| 82 | ...Including vertical precursor-product interface (e.g., horizontal Bridgman) | 98 | ..With a movement of substrate or vapor or gas supply means during growth (e.g., substrate rotation) |
| 83 | ...Having bottom-up crystallization (e.g., VFG, VGF) | 99 | ..With a chemical reaction (except ionization) in a disparate zone to form a precursor (e.g., transport processes) |

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| 100 | ...Fully-sealed or vacuum-maintained chamber (e.g., ampoule) | 207 | ..Crucibleless apparatus having means providing movement of discrete droplets or solid particles to thin-film precursor (e.g., Verneuil method) |
| 101 | ..Characterized by specified crystallography or arrangement of substrate (e.g., wafer cassette, Miller index) | 208 | ..Seed pulling |
| 102 | ..With significant flow manipulation or condition, other than merely specifying the components or their sequence or both | 209 | ...Including solid member shaping means other than seed or product (e.g., EDFA die) |
| 103 | ..Using an energy beam or field, a particle beam or field, or a plasma (e.g., ionization, PECVD, CBE, MOCBE, RF induction, laser) | 210 | ...Means for forming a hollow structure (e.g., tube, polygon) |
| 104 | ..Using an organic precursor (e.g., propane, metal-organic, MOCVD, MOVPE) | 211 | ...Including means forming a flat shape (e.g., ribbon) |
| 105 | ..Including change in a growth-influencing parameter (e.g., composition, temperature, concentration, flow rate) during growth (e.g., multilayer or junction or superlattice growing) | 212 |Pulling includes a horizontal component |
| 106 | ..With pretreatment or preparation of a base (e.g., annealing) | 213 | ...Including a sectioned crucible (e.g., double crucible, baffle) |
| 107 | ..With movement of substrate or vapor or gas supply means during growth | 214 | ...Including details of precursor replenishment |
| 108 | ..Using an energy beam or field, a particle beam or field, or a plasma (e.g., MBE) | 215 | ...Including sealing means details |
| 109 | ..Fully-sealed or vacuum-maintained chamber (e.g., ampoule) | 216 | ...Including a fully-sealed or vacuum-maintained crystallization chamber (e.g., ampoule) |
| 200 | APPARATUS | 217 | ...Including heating or cooling details (e.g., shield configuration) |
| 201 | ..With means for measuring, testing, or sensing | 218 | ...Including details of means providing product movement (e.g., shaft guides, servo means) |
| 202 | ..With responsive control means | 219 | ..Having means for producing a moving solid-liquid-solid zone |
| 203 | ..With a window or port for visual observation or examination | 220 | ...Including a solid member other than seed or product contacting the liquid (e.g., crucible, immersed heating element) |
| 204 | ..With means for treating single-crystal (e.g., heat treating) | 221 | ...Including details of a stabilizing feature |
| 205 | ..For forming a platelet shape or a small diameter, elongate, generally cylindrical shape (e.g., whisker, fiber, needle, filament) | 222 | ...Including heating or cooling details |
| 206 | ..For crystallization from liquid or supercritical state | 223 | ..Shape defined by a solid member other than seed or product (e.g., Bridgman-Stockbarger) |
| | | 224 | ..Including pressurized crystallization means (e.g., hydrothermal) |

CROSS-REFERENCE ART COLLECTIONS

900 APPARATUS CHARACTERIZED BY
COMPOSITION OR TREATMENT
THEREOF (E.G., SURFACE FINISH,
SURFACE COATING)

901 LEVITATION, REDUCED GRAVITY,
MICROGRAVITY, SPACE

902 SPECIFIED ORIENTATION, SHAPE,
CRYSTALLOGRAPHY, OR SIZE OF
SEED OR SUBSTRATE

903 DENDRITE OR WEB OR CAGE TECHNIQUE

904 LASER BEAM

905 ELECTRON BEAM

906 SPECIAL ATMOSPHERE OTHER THAN
VACUUM OR INERT

907 .Refluxing atmosphere

910 DOWNWARD PULLING

911 SEED OR ROD HOLDERS

912 REPLENISHING LIQUID PRECURSOR,
OTHER THAN A MOVING ZONE

913 GRAPHOEPIITAXY OR SURFACE
MODIFICATION TO ENHANCE
EPITAXY

914 CRYSTALLIZATION ON A CONTINUOUS
MOVING SUBSTRATE OR COOLING
SURFACE (E.G., WHEEL,
CYLINDER, BELT)

915 SEPARATING FROM SUBSTRATE

916 OXYGEN TESTING

917 MAGNETIC

918 SINGLE-CRYSTAL WAVEGUIDE

919 .Organic

920 SINGLE-CRYSTALS HAVING A HOLLOW
(E.G., TUBE, CONCAVO-CONVEX)
{C30B 29/66}

921 SMALL DIAMETER, ELONGATE,
GENERALLY CYLINDRICAL SINGLE-
CRYSTAL (E.G., WHISKERS,
NEEDLES, FILAMENTS, FIBERS,
WIRES) {C30B 29/62}

922 FREE-STANDING, FLAT SINGLE-
CRYSTAL (E.G., PLATELET,
PLATE, STRIP, DISK, TAPE,
SHEET, RIBBON) {C30B 29/64}

923 SINGLE-CRYSTAL OF COMPLEX
GEOMETRY (E.G., PATTERNED,
ELO) {C30B 29/66}

924 HOMOGENEOUS COMPOSITION PRODUCT
WITH ENLARGED CRYSTALS OR
ORIENTED-CRYSTALS (E.G.,
COLUMNAR)

925 ORGANIC COMPOUND CONTAINING
SINGLE-CRYSTAL {C30B 29/54}

926 .Tartrate containing (e.g.,
Rochelle salt) {C30B 29/56}

927 .Macromolecular compound
containing (i.e., more than
about 100 atoms) {C30B 29/58}

928 SINGLE-CRYSTAL OF PURE OR
INTENTIONALLY DOPED ELEMENT
{C30B 29/02}

929 .Carbon (e.g., diamond) {C30B 29/
04}

930 .Silicon from solid or gel state
{C30B 29/06}

931 .Silicon from liquid or
supercritical state {C30B 29/
06}

932 ..By pulling {C30B 29/06}

933 ..By moving zone (not Verneuil)
{C30B 29/06}

934 ..By liquid phase epitaxy {C30B
29/06}

935 .Silicon from vapor or gaseous
state {C30B 29/06}

936 .Germanium {C30B 29/08}

937 INORGANIC CONTAINING SINGLE-
CRYSTAL (E.G., COMPOUND,
MIXTURE, COMPOSITE) {C30B 29/
10}

938 .Gold, silver, or platinum
containing {C30B 29/52}

939 .Free metal or intermetallic
compound or silicon-metal
compound based, except arsenic
(e.g., alloys, SiGe, InSb)
{C30B 29/40, 29/52}

940 .Halide containing (e.g.,
fluorophlogopite, fluor-mica)
{C30B 29/12}

941 .Phosphorus-oxygen bond
containing (e.g., phosphate
(PO₄)) {C30B 29/14}

942 .Silicon-oxygen bond containing
(e.g., emerald, beryl, garnet,
mica) {C30B 29/16}

943 ..Quartz (SiO₂) {C30B 29/18}

944 .Oxygen compound containing
(e.g., yttria stabilized
zirconia) {C30B 29/16}

- 945 ..Containing A3Me5O12
(1.5(A2O3):2.5(Me2O3)),
wherein A is trivalent and
selected from the group Sc, Y,
La, Hf, or a rare earth metal
and Me is trivalent and
selected from the group Fe,
Ga, Sc, Cr, Co, or Al (e.g.,
non-silicate garnets) {C30B
29/28}
- 946 ..Containing AMe2O4 (AO:(Me2O3)),
wherein A is divalent and
selected from the group Mg,
Ni, Co, Mn, Zn, or Cd and Me is
trivalent and selected from
the group Fe, Ga, Sc, Cr, Co,
or Al (e.g., spinels) {C30B
29/26}
- 947 ..Containg AMeO3
((A2O3):(Me2O3)), wherein A is
trivalent and selected from
the group Sc, Y, La, Hf, or a
rare earth metal and Me is
trivalent and selected from
the group Fe, Ga, Sc, Cr, Co,
or Al (e.g., Perovskite
structure, ortho-ferrites)
{C30B29/24}
- 948 ..Niobate, vanadate, or tantalate
containing {C30B 29/30}
- 949 ..Titanate, germanate, molybdate,
or tungstate containing {C30B
29/32}
- 950 ..Aluminum containing (e.g.,
AL2O3, ruby, corundum,
sapphire, chrysoberyl) {C30B
29/20}
- 951 ..Carbide containing (e.g., SiC)
{C30B 29/36}
- 952 ..Nitride containing (e.g., GaN,
cBN) {C30B 29/38}
- 953 ..{B,Al,Ga,In,Tl}{P,As,Sb,Bi}
compound containing, except
intermetallics thereof (i.e.,
except {Al,Ga,In,Tl}{Sb,Bi})
{C30B 29/40}
- 954 ..Gallium arsenide containing
(e.g., GaAlAs, GaAs) {C30B 29/
42}
- 955 ..Gallium phosphide containing
{C30B 29/44}
- 956 ..{Zn,Cd,Hg}{S,Se,Te} compound
containing {C30B 29/46}
- 957 ..CdHgTe containing {C30B 29/48}
- 958 ..Cadmium sulfide containing
(e.g., ZnCdS) {C30B 29/50}

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